

<b>Notice of References Cited</b>	Application/Control No. 10/060,247	Applicant(s)/Patent Under Reexamination YUASA ET AL.	
	Examiner Kevin M Bernatz	Art Unit 1773	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0040781	11-2001	Tanaka et al.	360/324.12
	B	US-6,132,892	10-2000	Yoshikawa et al.	428/692
	C	US-2002/0073785	06-2002	Prakash et al.	73/862.041
	D	US-6,074,743	06-2000	Araki et al.	428/332
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-11-154609-A	06-1999	Japan	Yoshikawa et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Meguro, K., Hoshiya, H., Watanabe, K., Hamakawa, Y., and Fuyama, M. (IEEE Trans. Mag., 35(5), 1999, 2925 - 2927)
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.